

GaAlAs-Lumineszenzdiode (660 nm)

GaAlAs Light Emitting Diode (660 nm)

SFH 4860



Wesentliche Merkmale

- Hergestellt im Schmelzepitaxieverfahren
- Kathode galvanisch mit dem Gehäuseboden verbunden
- Hohe Zuverlässigkeit
- Gute spektrale Anpassung an Si-Fotoempfänger
- Hermetisch dichtes Metallgehäuse

Anwendungen

- Lichtschranken für Gleich- und Wechsellichtbetrieb
- IR-Gerätefernsteuerungen
- Sensorik
- Lichtgitter

Features

- Fabricated in a liquid phase epitaxy process
- Cathode is electrically connected to the case
- High reliability
- Matches all Si-Photodetectors
- Hermetically sealed package

Applications

- Photointerrupters
- IR remote control of various equipment
- Sensor technology
- Light-grille barrier

Typ Type	Bestellnummer Ordering Code	Gehäuse Package
SFH 4860	Q62702-P5053	18 A3 DIN 41876 (TO-18), Bodenplatte, Plankappe, Anschlüsse im 2.54-mm-Raster ($\frac{1}{10}$ "), Anodenkennzeichnung: Nase am Gehäuseboden 18 A3 DIN 870 (TO -18), flat glass cap, lead spacing 2.54 mm ($\frac{1}{10}$ "), anode marking: projection at package bottom

Grenzwerte ($T_A = 25\text{ °C}$)**Maximum Ratings**

Bezeichnung Parameter	Symbol Symbol	Wert Value	Einheit Unit
Betriebs- und Lagertemperatur Operating and storage temperature range	$T_{op}; T_{stg}$	– 40 ... + 100	°C
Sperrschichttemperatur Junction temperature	T_j	125	°C
Sperrspannung Reverse voltage	V_R	3	V
Durchlaßstrom Forward current	I_F	50	mA
Stoßstrom, $t_p = 10\text{ }\mu\text{s}$, $D = 0$ Surge current	I_{FSM}	1	A
Verlustleistung Power dissipation	P_{tot}	140	mW
Wärmewiderstand Thermal resistance	R_{thJA} R_{thJC}	450 160	K/W K/W

Kennwerte ($T_A = 25\text{ °C}$)**Characteristics**

Bezeichnung Parameter	Symbol Symbol	Wert Value	Einheit Unit
Wellenlänge der Strahlung Wavelength at peak emission $I_F = 50\text{ mA}$	λ_{peak}	660	nm
Spektrale Bandbreite bei 50% von I_{max} Spectral bandwidth at 50% of I_{max} $I_F = 50\text{ mA}$	$\Delta\lambda$	25	nm
Abstrahlwinkel Half angle	φ	± 50	Grad deg.
Aktive Chipfläche Active chip area	A	0.106	mm ²
Abmessungen der aktiven Chipfläche Dimension of the active chip area	$L \times B$ $L \times W$	0.325×0.325	mm
Schaltzeiten, I_e von 10% auf 90% und von 90% auf 10%, bei $I_F = 50\text{ mA}$, $R_L = 50\text{ }\Omega$ Switching times, I_e from 10% to 90% and from 90% to 10%, $I_F = 50\text{ mA}$, $R_L = 50\text{ }\Omega$	t_r, t_f	100	ns

Kennwerte ($T_A = 25\text{ °C}$)

Characteristics (cont'd)

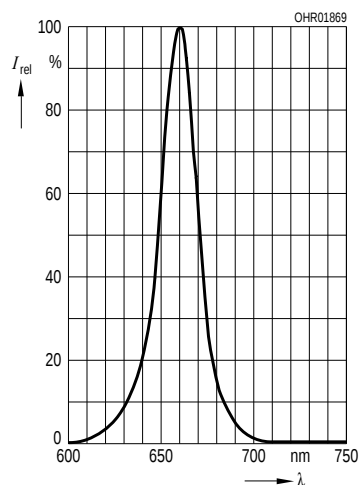
Bezeichnung Parameter	Symbol Symbol	Wert Value	Einheit Unit
Kapazität, $V_R = 0\text{ V}$, $f = 1\text{ MHz}$ Capacitance	C_o	30	pF
Durchlaßspannung, $I_F = 50\text{ mA}$, $t_p = 20\text{ ms}$ Forward voltage	V_F	2 (≤ 2.8)	V
Sperrstrom, $V_R = 3\text{ V}$ Reverse current	I_R	0.01 (≤ 10)	μA
Gesamtstrahlungsfluß, $I_F = 50\text{ mA}$, $t_p = 20\text{ ms}$ Total radiant flux	Φ_e	3	mW
Temperaturkoeffizient von I_e bzw. Φ_e , $I_F = 50\text{ mA}$ Temperature coefficient of I_e or Φ_e , $I_F = 50\text{ mA}$	TC_I	- 0.4	%/K
Temperaturkoeffizient von V_F , $I_F = 50\text{ mA}$ Temperature coefficient of V_F , $I_F = 50\text{ mA}$	TC_V	- 3	mV/K
Temperaturkoeffizient von λ , $I_F = 50\text{ mA}$ Temperature coefficient of λ , $I_F = 50\text{ mA}$	TC_λ	+ 0.16	nm/K

Strahlstärke I_e in Achsrichtunggemessen bei einem Raumwinkel $\Omega = 0.01\text{ sr}$ **Radiant Intensity I_e in Axial Direction**at a solid angle of $\Omega = 0.01\text{ sr}$

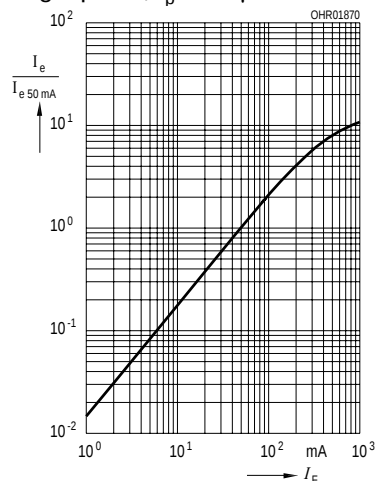
Bezeichnung Parameter	Symbol	Werte Values	Einheit Unit
Strahlstärke Radiant intensity $I_F = 50\text{ mA}$, $t_p = 20\text{ ms}$	$I_{e\text{ min}}$ $I_{e\text{ typ}}$	≥ 0.63 1.3	mW/sr mW/sr
Strahlstärke Radiant intensity $I_F = 1\text{ A}$, $t_p = 100\text{ }\mu\text{s}$	$I_{e\text{ typ}}$	15	mW/sr

Relative Spectral Emission

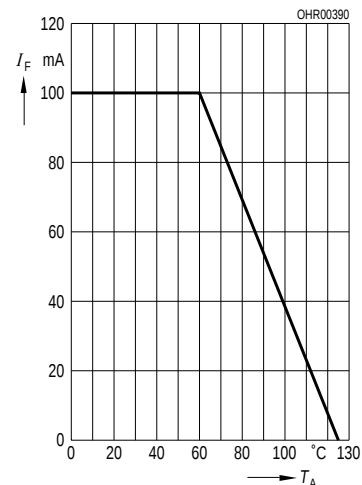
$$I_{\text{rel}} = f(\lambda)$$



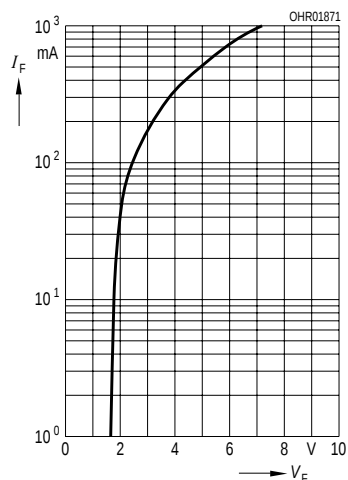
$$\text{Radiant Intensity } \frac{I_e}{I_{e \text{ 50 mA}}} = f(I_F)$$

Single pulse, $t_p = 20 \mu\text{s}$ **Max. Permissible Forward Current**

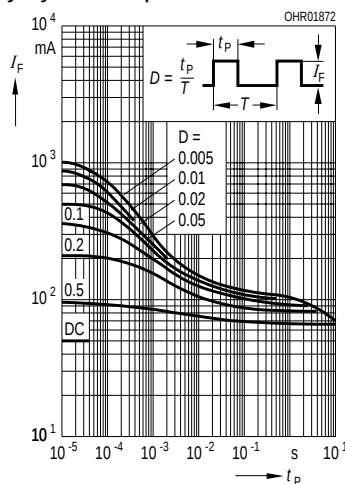
$$I_F = f(T_C), R_{\text{thJC}} = 160 \text{ K/W}$$

**Forward Current**

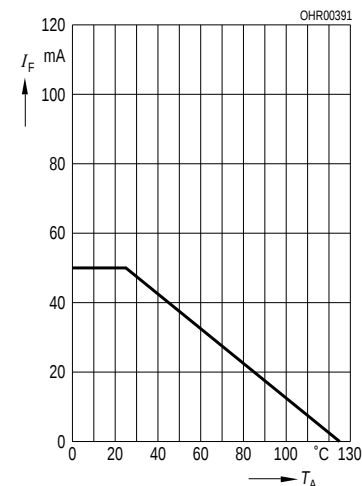
$$I_F = f(V_F), \text{ single pulse, } t_p = 20 \mu\text{s}$$

**Permissible Pulse Handling Capability**

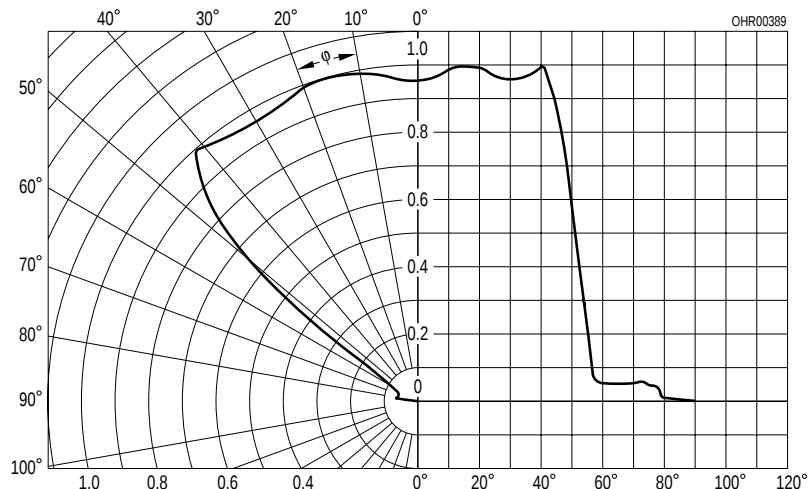
$$I_F = f(\tau), T_A = 25^\circ\text{C}, \text{ duty cycle } D = \text{parameter}$$

**Max. Permissible Forward Current**

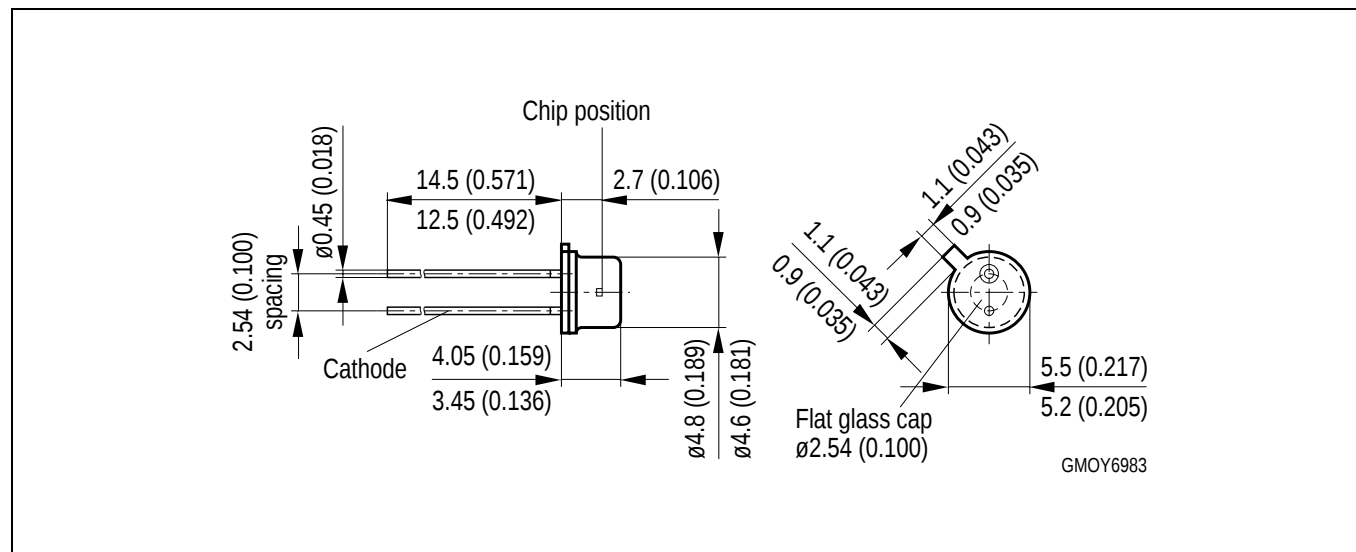
$$I_F = f(T_A), R_{\text{thJA}} = 450 \text{ K/W}$$

**Radiation Characteristics**

$$I_{\text{rel}} = f(\varphi)$$



Maßzeichnung Package Outlines



Maße werden wie folgt angegeben: mm (inch) / Dimensions are specified as follows: mm (inch).

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Please use the recycling operators known to you. We can also help you – get in touch with your nearest sales office. By agreement we will take packing material back, if it is sorted. You must bear the costs of transport. For packing material that is returned to us unsorted or which we are not obliged to accept, we shall have to invoice you for any costs incurred.

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